

USB A TYPE UPRIGHT REVERSE CONNECTOR

1.0 SCOPE

This specification covers the requirements for product performance and test methods of USB A TYPE UPRIGHT REVERSE (Universal Serial Bus Revision 2.0) CONNECTOR.

2.0 PRODUCT DESCRIPTION

2.1 PRODUCT NAME AND SERIES NUMBER (S)

2.1.1 PRODUCT NAME: USB A TYPE UPRIGHT REVERSE CONNECTOR 2.1.2 SERIES NUMBER: 48204

2.2 DIMENSIONS, MATERIALS, PLATINGS AND MARKINGS

See drawing no: SD-48204-001

3.0 RATINGS

- 4.1 VOLTAGE 30 Volts AC (RMS) {or 30 Volts DC}
- 4.2 CURRENT <u>1.5</u>Amps
- **4.3 TEMPERATURE** Operating: - <u>55</u>°C to + <u>85</u>°C

<u>REVISION:</u>	<u>ECR/ECN INFORMATION:</u> <u>EC No:</u> SH2005-0330 <u>DATE:</u> 2005/1/18	USI REVEI	USB A TYPE UPRIGHT REVERSE CONNECTOR				
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4.0 PERFORMANCE

5.1 ELECTRICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
1	Low Level Contact Resistance	EIA 364-23 Mate connectors: apply a maximum voltage of 20 mV and a current of 100 mA.	30 milliohms MAXIMUM
2	Insulation Resistance	EIA 364-21 Unmate & unmount connectors: apply a voltage of 500 VDC between adjacent terminals and between terminals to ground	1000 Megohms MINIMUM
3	Dielectric Withstanding Voltage	EIA 364-20 Un-mate connectors: apply a voltage of 500 volts VAC for 1 minute between adjacent terminals and between terminals to ground.	No breakdown; current leakage < 0.5 mA
4	Contact Capacitance	EIA-364-30 Test between adjacent circuits of unmated connector at 1 MHz. The object of this test is to detail a standard method to determine the capacitance between conductive elements of a USB connector.	2 pF Maximum per Contact
5	Contact Current Rating	EIA 364-70 Method B Mate connectors : measure the temperature rise at the rated current (1.5A).	Temperature rise : 30 □ maximum

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5.2 MECHANICAL REQUIREMENTS (continued)

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
6	Connector Mate And Un-mate Forces	EIA 364-13 Mate and un-mate connector (male to	Mating Force: 35 N MAXIMUM
		female) at a rate of 20 mm (1 ± ¼ inch) per minute.	Un-mating Force: 10 N MINIMUM
7	Durability	EIA-364-09 Mate and un-mate Connector assemblies for 1500 cycles at maximum rated of 300 cycles per hour.	Shall meet visual requirement, show no physical damage
8	Vibration (Random)	EIA 364-28, test condition VII. Mate connectors and vibrate per	 No discontinuities of 1 microsecond or longer duration Shall meet visual requirement, show no physical damage.
9	Mechanical Shock	EIA 364-27 Test Condition H Subject mated connectors to 30G's half- sine shock pulses of 11ms duration. Three shocks in each direction applied along three mutually perpendicular planes, 18 total shock.	 No discontinuities of 1 microsecond or longer duration Shall meet visual requirement, show no physical damage.

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5.3 ENVIRONMENTAL REQUIREMENTS

TEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
10	Humidity	EIA 364-31 Test condition A method III Subject mated connectors to 60 cycles temperature between -25°C to +65°C with 90 to 95% RH	 Dielectric Withstanding Voltage: No Breakdown at 500 VAC Insulation Resistance: 1000 Megohms MINIMUM Visual: No Damage
11	Shock (Thermal)	EIA 364-32, Test Condition I Subject mated connectors to ten cycles between -55° C to $+85^{\circ}$ C.	 Dielectric Withstanding Voltage: No Breakdown at 500 VAC Insulation Resistance: 1000 Megohms MINIMUM Visual: No Damage
12	Temperature Life	EIA 364-17 Test Condition 2 Method A Subject mated connectors to temperature life at 85°C for 500hours	 30 milliohms MAXIMUM Shall meet visual requirement, show no physical damage.
13	Solderability	EIA 364-52 After one hour steam aging.	The surface of the portion to be soldered shall at least 95% covered with new solder coating
14	Resistance To Solder Heat	MIL-STD-202F, Method 210A, Test Condition B. for WAVE SOLDERING Pre-heat: 80° C, 60 Seconds Temperature: $265 \pm 5^{\circ}$ C Immersion duration: 10 ± 1 sec.	No mechanical defect on housing or other parts.

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TEST SEQUENCES IDENTIFICATION

	Test Group												
Test Item	Test Description		А		3	С		D		Е		F	
rest item	Examination of product	1	9	1	5	1	9	1	3	1 3	3	1	3
1	Low Level Contact Resistance	3	7	2	4								
2	Insulation Resistance					3	7						
3	Dielectric Withstanding Voltage					4	8						
4	Contact Capacitance					2	2						
5	Contact Current Rating									2			
6	Mating & Un-mating Force	2	8										
7	Durability	Z	1										
8	Random Vibration	6	3							,			
9	Mechanical Shock	5	5										
10	Humidity					Ę	5						
11	Thermal Shock					6	6						
12	Temperature Life			3	3								
13	Solder ability								2				
14	Resistance to solder heat											2	
Number of Test Samples (Minimum)	5	Ę	5	Ę	5	Ę	5	į	5	5		5	1

Note:

a. Samples shall be prepare in accordance with applicable manufacture's instructions and shall be selected at random

from current production.

b. Precondition samples with 3 cycles durability.

c. All the tests shall be performed in the sequence.

5.0 PACKAGING

Parts shall be packaged to protect against damage during handling, transit and storage.

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单击下面可查看定价,库存,交付和生命周期等信息

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